IN THE CLAIMS:

Please add new claims 30-37 as follows.

30. (new) Method enabling a command to switch a measure mode to be entered in a dimensional-measuring column provided with a probe tip,

wherein said command to switch the measure mode is entered by means of deliberate handling operations of a height-command crank.

31. (new) Method according to claim 30, wherein said command to switch the measure mode enables said dimension-measuring column to pass into a mode to search for a turn-back point of said piece to be measured.

32. (new) Method according to claim 30, wherein said command to switch the measure mode results in modifying the measuring accuracy and/or resolution.

33. (new) The method according to claim 30, wherein a status of the display of said dimension-measuring column is modified following said command to switch the measure mode so as to indicated the status of a pressing force of said probe tip against a piece to be measured.

34. (new) The method of claim 30, wherein said command to switch the measure mode is entered by pressing said probe tip against a piece to be measured during a time interval shorter than a predetermined value.

35. (new) Dimension-measuring column, comprising:

a probe tip designed for being brought into contact with a piece to be measured,

a height-command crank for displacing said probe tip,

a measuring and displaying system that allows the position of said probe tip to be determined and displayed,

wherein a command to switch the measure mode is entered by means of deliberate handling operations of the height-command crank.

36. (new) The dimension-measuring column of claim 35, wherein said command to switch the measure mode enables a measuring column to pass into a mode to search for a turn-back point of said piece to be measured.

37. (new) The dimension-measuring column of claim 35, wherein said mode switch command results in modifying the measuring accuracy and/or resolution.